Searcn Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/601,085	JAIN ET AL.
Examiner	Art Unit
Matthew D. Matzek	1771

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	1/13/2005	MM
Inventor Search	1/13/2005	ММ
IDS	1/14/2005	ММ
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